

Title of Change:	Copper wire conversion for LB1940T.				
Proposed first ship date:	16 November 2015				
Contact information:	Contact your local ON Semiconductor Sales Office or < Tsutomu Shimazaki@onsemi.com > < Takashi.Harashima@onsemi.com>< Takeshi2.Hoshino@onsemi.com>< Kazumi.Onda@onsemi.com> < Shinya Okada@onsemi.com>< Yoshiyuki Nunokawa@onsemi.com>				
Samples:	Contact your local ON Semiconductor Sales Office. < jun.hasunuma@onsemi.com>				
Type of notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customers. IPCNs are issued at least 120 days prior to implementation of the change. An IPCN is advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change. In case of questions, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>				
Change Part Identification:	Affected products will be identified with date code.				
Change category:	🗌 Wafer Fab Change 🛛 Assembly Change 🗌 Test Change 🗌 Other				
Change Sub-Category(s): <ul> <li>Manufacturing Site Change/Addition</li> <li>Material Change</li> <li>Shipping/Packaging/Marking</li> <li>Other:</li> </ul>					
Sites Affected: All site(s) I not applicab	le ON Semiconductor site(s) : ON Tarlac City, Philippine	es	External Foundry/Subcon site(s)		
Description and Purpose: This is an Initial Process Change Notification to announce Gold wire connecting chip and Lead will be changed to Copper wire. The electrical characteristic specification is not impacted of this change.					
Qualification Plan: Estimated date for qualification completion: 28 August 2015 Package name : TSSOP20(225mil)					
Test Items	Test Condition		Test Time		
High Temperature Operating Life	Tj=Tjmax,Vcc=Operatingma	ах	1000hrs		
Temperature Humidity Bias *	Ta=85degC,RH=85%, Vcc=Recomm	nended T	1000hrs		
Temperature Cycle *	$Ta=-65degC(30min) \Leftrightarrow Ta=150degC(30min)$		500cycles		
Pressure Cooker *	Ta=121degC,RH=100% ,205kPa		50hrs		
High Temperature Storage	Ta=150degC		1000hrs		
Resistance to Soldering heat (Reflow Soldering)	255degC,10s (Peak260degC)		2times		
Notes: The test items with * mark are put into operation after the reflow soldering (at 255degC for 10seconds) -> SMD Temperature Humidity Bias Test: PD>=0.1W -> Intermittent power application consists of 1h ON and 3h OFF. Judgment Criteria : Judgment Criteria are due to the limits of the electrical characteristics in the detail specification.					
List of Affected Standard Parts:					
Part Number		Qualification Vehicle			
LB1940T-TLM-H		LB1940T-TLM-H			